SLCS008A – OCTOBER 1979 – REVISED OCTOBER 1991

- Fast Response Times
- Improved Gain and Accuracy
- Fanout to 10 Series 54/74 TTL Loads
- Strobe Capability
- Short-Circuit and Surge Protection
- Designed to Be Interchangeable With National Semiconductor LM306

description

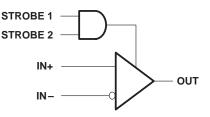
The LM306 is a high-speed voltage comparator with differential inputs, a low-impedance highsink-current (100 mA) output, and two strobe inputs. This device detects low-level analog or digital signals and can drive digital logic or lamps and relays directly. Short-circuit protection and surge-current limiting is provided.

A low-level input at either strobe causes the output to remain high regardless of the differential input.When both strobe inputs are either open or at a high logic level, the output voltage is controlled by the differential input voltage. The circuit will operate with any negative supply voltage between -3 V and -12 V with little difference in performance.

The LM306 is characterized for operation from 0° C to 70° C.

D OR P PACKAGE (TOP VIEW)						
GND [1	8] V _{CC+}			
IN+ [2	7] OUT			
IN- [3	6] STROBE 2			
V _{CC-} [4	5] STROBE 1			

functional block diagram



AVAILABLE OPTIONS

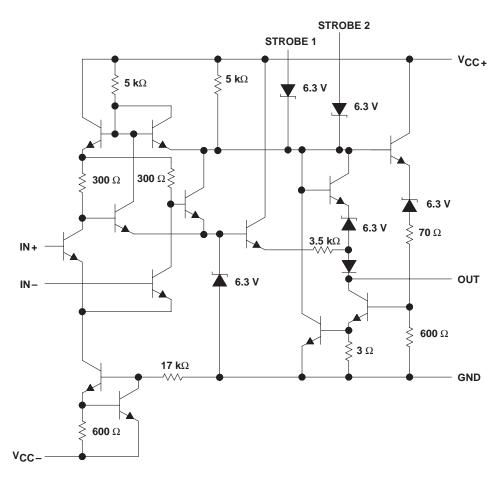
	Viemov	PACKAGE			
TA	V _{IO} max at 25°C	SMALL OUTLINE (D)	PLASTIC DIP (P)		
0°C to 70°C	5 mV	LM306D	LM306P		

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SLCS008A – OCTOBER 1979 – REVISED OCTOBER 1991

schematic



Resistor values are nominal.



SLCS008A - OCTOBER 1979 - REVISED OCTOBER 1991

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Cumplus (and Note 1)	45 \/
Supply voltage, V _{CC+} (see Note 1)	
Supply voltage, V _{CC} (see Note 1)	–15 V
Differential input voltage, VID (see Note 2)	$\ldots \ldots \pm 5 \; V$
Input voltage, V _I (either input, see Notes 1 and 3)	$\ldots \ldots \pm 7 \; V$
Strobe voltage range (see Note 1)	0 V to V _{CC+}
Output voltage, V _O (see Note 1)	24 V
Voltage from output to V _{CC}	30 V
Duration of output short circuit to ground (see Note 4)	10 s
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	
Storage temperature range	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages and the voltage from the output to V_{CC}, are with respect to the network ground. 2. Differential voltages are at IN+ with respect to IN-.

3. The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 7 V, whichever is less.

4. The output may be shorted to ground or either power supply.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C	DERATING	DERATE	T _A = 70°C
	POWER RATING	FACTOR	ABOVE T _A	POWER RATING
D	600 mW	5.8 mW/°C	46°C	464 mW
P	600 mW	8.0 mW/°C	75°C	600 mW



SLCS008A – OCTOBER 1979 – REVISED OCTOBER 1991

electrical characteristics at specified free-air temperature, $V_{CC+} = 12 V$, $V_{CC-} = -3 V$ to -12 V (unless otherwise noted)

	PARAMETER	TEST CON	DITIONS [†]	T _A ‡	MIN	TYP	MAX	UNIT	
Vie	Input offect voltage	B = < 200 O		25°C		1.6§	5	mV	
V _{IO} Input offset voltage		$R_{S} \le 200 \Omega$		Full range			6.5	mv	
αVIO	Average temperature coefficient of input offset voltage	R _S = 50 Ω,	See Note 5	Full range		5	20	μV/°C	
		1		25°C		1.8	5		
IIO	Input offset current	See Note 5		MIN		1	7.5	μA	
				MAX		0.5	5		
	Average temperature coefficient of	See Note F	See Note 5			24	100	nA/°C	
αΙΙΟ	input offset current	See Note 5				15	50		
1				MIN to 25°C			40		
IIB Input bias current		$V_{O} = 0.5 V$ to 5 V		25°C to MAX		16	25	μA	
I _{IL(S)}	Low-level strobe current	V _(strobe) = 0.4 V		Full range		-1.7	-3.2	mA	
VIH(S)	High-level strobe voltage			Full range	2.2			V	
VIL(S)	Low-level strobe voltage			Full range			0.9	V	
VICR	Common-mode input voltage range	$V_{\rm CC-} = -7 V to -1$	12 V	Full range	±5			V	
VID	Differential input voltage range			Full range	±5			V	
A _{VD}	Large-signal differential voltage amplification	$V_{O} = 0.5 V \text{ to } 5 V,$	No load	25°C		40		V/mV	
VOH	High-level output voltage	I _{OH} = -400 μA	V _{ID} = 8 mV	Full range	2.5		5.5	V	
	Low-level output voltage	I _{OL} = 100 mA	$V_{ID} = -7 \text{ mV}$	25°C		0.8	2		
VOL		I _{OL} = 50 mA	$V_{ID} = -7 \text{ mV}$	Full range			1	V	
		I _{OL} = 16 mA	$V_{ID} = -8 \text{ mV}$	Full range			0.4		
	High-level output voltage		$V_D = 7 \text{ mV}$	MIN to 25°C		0.02	2		
ЮН		$V_{OH} = 8 V \text{ to } 24 V$	V _{ID} = 8 mV	25°C to MAX			100	μA	
ICC+	Supply current from V _{CC+}	$V_{ID} = -5 \text{ mV},$	No load	Full range		6.6	10	mA	
ICC-	Supply current from V _{CC}	No load		Full range		-1.9	-3.6	mA	

[†] Unless otherwise noted, all characteristics are measured with both strobes open.

[‡]Full range is 0°C to 70°C. MIN is 0°C. MAX is 70°C.

§ This typical value is at V_{CC+} = 12 V, V_{CC-} = -6 V.

NOTE 5: The offset voltages and offset currents given are the maximum values required to drive the output down to the low range (V_{OL}) or up to the high range (V_{OH}). These parameters actually define an error band and take into account the worst-case effects of voltage gain and input impedance.

switching characteristics, V_{CC+} = 12 V, V_{CC-} = -6 V, T_A = 25°C

PARAMETER	TEST CONDITIONS [†]		MIN	TYP	MAX	UNIT
Response time, low-to-high-level output	$R_L = 390 \ \Omega$ to 5 V, $C_L = 15 \ p$, See Note 6		28	40	ns

[†] All characteristics are measured with both strobes open.

NOTE 6: The response time specified is for a 100-mV input step with 5-mV overdrive and is the interval between the input step function and the instant when the output crosses 1.4 V.

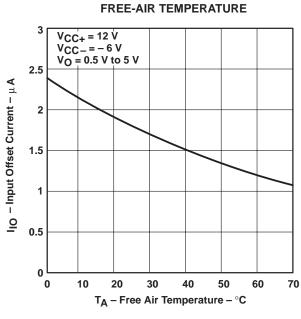


SLCS008A - OCTOBER 1979 - REVISED OCTOBER 1991

TYPICAL CHARACTERISTICS

Table of Graphs

			FIGURE
I _{IB}	Input bias current	vs Free-air temperature	1
IIO	Input offset current	vs Free-air temperature	2
VOH	High-level output voltage	vs Free-air temperature	3
VOL	Low-level output voltage	vs Free-air temperature	4
Vo	Output voltage	vs Differential input voltage	5
lo	Output current	vs Differential input voltage	6
AVD	Large-signal differential voltage amplification	vs Free-air temperature	7
IOS	Short-circuit output current	vs Free-air temperature	8
	Output response	vs Time	9, 10
ICC+	Positive supply current	vs Positive supply voltage	11
ICC-	Negative supply current	vs Negative supply voltage	12
PD	Total power dissipation	vs Free-air temperature	13



INPUT OFFSET CURRENT

vs

Figure 1

INPUT BIAS CURRENT vs FREE-AIR TEMPERATURE

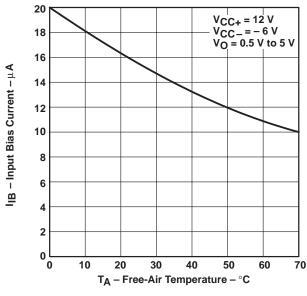
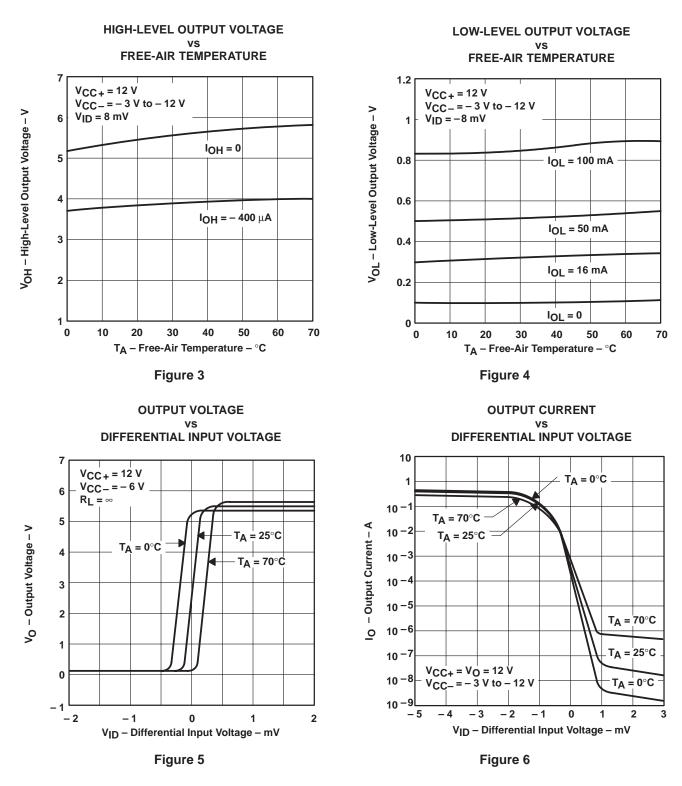


Figure 2

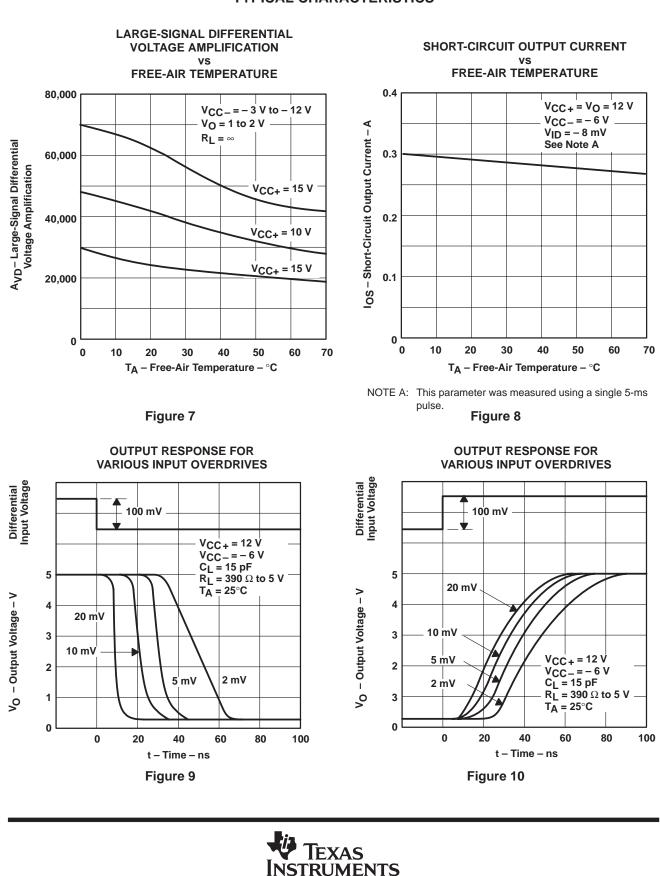


SLCS008A – OCTOBER 1979 – REVISED OCTOBER 1991



TYPICAL CHARACTERISTICS

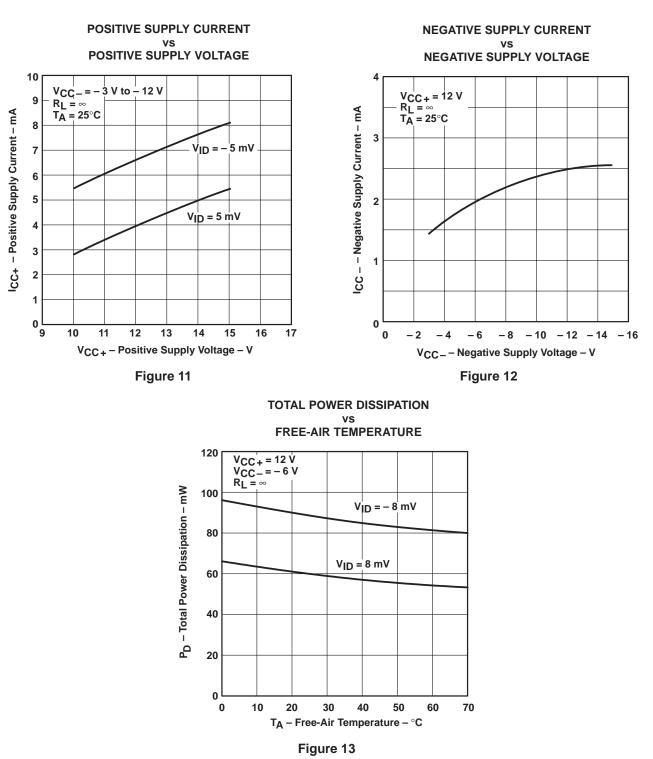
SLCS008A - OCTOBER 1979 - REVISED OCTOBER 1991



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

TYPICAL CHARACTERISTICS

SLCS008A – OCTOBER 1979 – REVISED OCTOBER 1991



TYPICAL CHARACTERISTICS



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated